

TEST REPORT

FCC Sub6 n12 Test for SM-F741U
Certification

APPLICANT
SAMSUNG Electronics Co., Ltd.

REPORT NO.
HCT-RF-2404-FC026-R1

DATE OF ISSUE
May 3, 2024

Tested by
Jae Ryang Do



Technical Manager
Jong Seok Lee



HCT CO., LTD.
Bongjai Huh
BongJai Huh / CEO



HCT CO.,LTD.

2-6, 73, 74, Seoicheon-ro 578beon-gil, Majang-myeon, Icheon-si, Gyeonggi-do, 17383 KOREA
Tel. +82 31 645 6300 Fax. +82 31 645 6401

**TEST
REPORT**

REPORT NO.
HCT-RF-2404-FC026-R1

DATE OF ISSUE
May 03, 2024

Additional Model
SM-F741U1

Applicant **SAMSUNG Electronics Co., Ltd.**
129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Rep. of Korea

Product Name Mobile Phone
Model Name SM-F741U

Date of Test February 27, 2024 ~ April 19, 2024

FCC ID A3LSMF741U

Location of Test Permanent Testing Lab On Site Testing
(Address: 74, Seoicheon-ro 578beon-gil, Majang-myeon, Icheon-si, Gyeonggi-do, 17383 Republic of Korea)

FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)

FCC Rule Part(s): § 27

REVISION HISTORY

The revision history for this test report is shown in table.

Revision No.	Date of Issue	Description
0	April 26, 2024	Initial Release
1	May 03, 2024	Revised the date of test (Page 2.)

Notice

Content

The measurements shown in this report were made in accordance with the procedures specified in CFR47 section § 2.947. I assume full responsibility for the accuracy and completeness of these measurements, and for the qualifications of all persons taking them.

HCT CO., LTD. Certifies that no party to this application has subject to a denial of Federal benefits that includes FCC benefits pursuant to section 5301 of the Anti-Drug Abuse Act of 1998, 21 U.S.C. 853(a)

The results shown in this test report only apply to the sample(s), as received, provided by the applicant, unless otherwise stated.

The test results have only been applied with the test methods required by the standard(s).

When confirmation of authenticity of this test report is required, please contact www.hct.co.kr

The test results in this test report are not associated with the ((KS Q) ISO/IEC 17025) accreditation by KOLAS (Korea Laboratory Accreditation Scheme) / A2LA (American Association for Laboratory Accreditation) that are under the ILAC (International Laboratory Accreditation Cooperation) Mutual Recognition Agreement (MRA).

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MEASUREMENT REPORT

1. GENERAL INFORMATION

Applicant Name:	SAMSUNG Electronics Co., Ltd.
Address:	129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Rep. of Korea
FCC ID:	A3LSMF741U
Application Type:	Certification
FCC Classification:	PCS Licensed Transmitter Held to Ear (PCE)
FCC Rule Part(s):	§ 22
EUT Type:	Mobile phone
Model(s):	SM-F741U
Additional Model(s)	SM-F741U1
SCS(kHz):	15
Bandwidth(MHz):	5, 10, 15
Waveform:	CP-OFDM, DFT-S-OFDM
Modulation:	DFT-S-OFDM: PI/2 BPSK, QPSK, 16QAM, 64QAM, 256QAM CP-OFDM: QPSK, 16QAM, 64QAM, 256QAM
Tx Frequency:	701.5 MHz – 713.5 MHz (Sub6 n12 (5 MHz)) 704.0 MHz – 711.0 MHz (Sub6 n12 (10 MHz)) 706.5 MHz – 708.5 MHz (Sub6 n12 (15 MHz))
Date(s) of Tests:	February 27, 2024 ~ April 19, 2024
Serial number:	Radiated : R3CX20KJSJW Conducted : 7B5599BDA3507ECE

1.1. MAXIMUM OUTPUT POWER

Mode (MHz)	Tx Frequency (MHz)	Emission Designator	Modulation	ERP	
				Max. Power (W)	Max. Power (dBm)
Sub6 n12 (5)	701.5 – 713.5	4M60G7D	PI/2 BPSK	0.093	19.70
		4M56G7D	QPSK	0.091	19.59
		4M58W7D	16QAM	0.070	18.47
		4M59W7D	64QAM	0.052	17.14
		4M58W7D	256QAM	0.029	14.59
Sub6 n12 (10)	704.0 – 711.0	8M96G7D	PI/2 BPSK	0.092	19.66
		8M94G7D	QPSK	0.091	19.60
		8M95W7D	16QAM	0.070	18.45
		8M97W7D	64QAM	0.052	17.14
		8M94W7D	256QAM	0.028	14.47
Sub6 n12 (15)	706.5 – 708.5	13M4G7D	PI/2 BPSK	0.092	19.65
		13M4G7D	QPSK	0.092	19.63
		13M4W7D	16QAM	0.071	18.54
		13M5W7D	64QAM	0.052	17.18
		13M4W7D	256QAM	0.028	14.53

2. INTRODUCTION

2.1. DESCRIPTION OF EUT

The EUT was a Mobile Phone with GSM/GPRS/EGPRS/UMTS and LTE, Sub 6, mmWave. It also supports IEEE 802.11 a/b/g/n/ac/ax (20/40/80/160 MHz), Bluetooth(iPA, ePA), BT LE(iPA, ePA), NFC, WPT, WIFI 6E.

2.2. MEASURING INSTRUMENT CALIBRATION

The measuring equipment, which was utilized in performing the tests documented herein, has been calibrated in accordance with the manufacturer's recommendations for utilizing calibration equipment, which is traceable to recognized national standards.

2.3. TEST FACILITY

The Fully-anechoic chamber and conducted measurement facility used to collect the radiated data are located at the **74, Seoicheon-ro 578beon-gil, Majang-myeon, Icheon-si, Gyeonggi-do, 17383, Rep. of KOREA.**

3. DESCRIPTION OF TESTS

3.1 TEST PROCEDURE

Test Description	Test Procedure Used
Occupied Bandwidth	- KDB 971168 D01 v03r01 – Section 4.3 - ANSI C63.26-2015 – Section 5.4.4
Band Edge	- KDB 971168 D01 v03r01 – Section 6.0 - ANSI C63.26-2015 – Section 5.7
Spurious and Harmonic Emissions at Antenna Terminal	- KDB 971168 D01 v03r01 – Section 6.0 - ANSI C63.26-2015 – Section 5.7
Conducted Output Power	- N/A (See SAR Report)
Peak- to- Average Ratio	- KDB 971168 D01 v03r01 – Section 5.7 - ANSI C63.26-2015 – Section 5.2.3.4
Frequency stability	- ANSI C63.26-2015 – Section 5.6
Effective Radiated Power/ Effective Isotropic Radiated Power	- KDB 971168 D01 v03r01 – Section 5.2 & 5.8 - ANSI/TIA-603-E-2016 – Section 2.2.17
Radiated Spurious and Harmonic Emissions	- KDB 971168 D01 v03r01 – Section 6.2 - ANSI/TIA-603-E-2016 – Section 2.2.12

3.2 RADIATED POWER

Test Overview

Radiated tests are performed in the Fully-anechoic chamber.

The equipment under test is placed on a non-conductive table 3-meters away from the receive antenna in accordance with ANSI/TIA-603-E-2016 Clause 2.2.17.

Test Settings

1. Radiated power measurements are performed using the signal analyzer's "channel power" measurement capability for signals with continuous operation.
2. RBW = 1 – 5 % of the expected OBW, not to exceed 1 MHz
3. VBW \geq 3 x RBW
4. Span = 1.5 times the OBW
5. No. of sweep points > 2 x span / RBW
6. Detector = RMS
7. Trigger is set to "free run" for signals with continuous operation with the sweep times set to "auto".
8. The integration bandwidth was roughly set equal to the measured OBW of the signal for signals with continuous operation.
9. Trace mode = trace averaging (RMS) over 100 sweeps
10. The trace was allowed to stabilize

Test Note

1. The turntable is rotated through 360 degrees, and the receiving antenna scans in order to determine the level of the maximized emission.
2. A half wave dipole is then substituted in place of the EUT. For emissions above 1 GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator and the previously recorded signal was duplicated.

The power is calculated by the following formula;

$$P_d \text{ (dBm)} = P_g \text{ (dBm)} - \text{cable loss (dB)} + \text{antenna gain (dB)}$$

Where: P_d is the dipole equivalent power and P_g is the generator output power into the substitution antenna.

3. The maximum value is calculated by adding the forward power to the calibrated source plus its appropriate gain value.
These steps are repeated with the receiving antenna in both vertical and horizontal polarization. the difference between the gain of the horn and an isotropic antenna are taken into consideration
4. The EUT was tested in three orthogonal planes(X, Y, Z) and in all possible test configurations and positioning.
5. All measurements are performed as RMS average measurements while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies.

3.3 RADIATED SPURIOUS EMISSIONS

Test Overview

Radiated tests are performed in the Fully-anechoic chamber.

Radiated Spurious Emission Measurements at 3 meters by Substitution Method according to ANSI/TIA-603-E-2016.

Test Settings

1. RBW = 100 kHz for emissions below 1 GHz and 1 MHz for emissions above 1 GHz
2. VBW \geq 3 x RBW
3. Span = 1.5 times the OBW
4. No. of sweep points $>$ 2 x span / RBW
5. Detector = Peak
6. Trace mode = Max Hold
7. The trace was allowed to stabilize
8. Test channel : Low/ Middle/ High
9. Frequency range : We are performed all frequency to 10th harmonics from 9 kHz.

Test Note

1. Measurements value show only up to 3 maximum emissions noted, or would be lesser if no specific emissions from the EUT are recorded (ie: margin $>$ 20 dB from the applicable limit) and considered that's already beyond the background noise floor.
2. The EUT was tested in three orthogonal planes(X, Y, Z) and in all possible test configurations and positioning.
The worst case emissions are reported with the EUT positioning, modulations, RB sizes and offsets, and channel bandwidth configurations shown in the test data
3. For spurious emissions above 1 GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator and the previously recorded signal was duplicated.

The spurious emissions is calculated by the following formula;

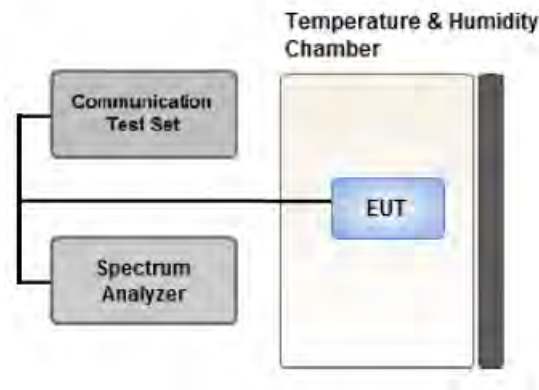
$$\text{Result}_{(dBm)} = P_g_{(dBm)} - \text{cable loss}_{(dB)} + \text{antenna gain}_{(dBi)}$$

Where: P_g is the generator output power into the substitution antenna.

If the fundamental frequency is below 1 GHz, RF output power has been converted to EIRP.

$$\text{EIRP}_{(dBm)} = \text{ERP}_{(dBm)} + 2.15$$

3.4 PEAK- TO- AVERAGE RATIO



Test setup

① CCDF Procedure for PAPR

Test Settings

1. Set resolution/measurement bandwidth \geq signal's occupied bandwidth;
2. Set the number of counts to a value that stabilizes the measured CCDF curve;
3. Set the measurement interval as follows:
 - for continuous transmissions, set to 1 ms,
 - or burst transmissions, employ an external trigger that is synchronized with the EUT burst timing sequence, or use the internal burst trigger with a trigger level that allows the burst to stabilize and set the measurement interval to a time that is less than or equal to the burst duration.
4. Record the maximum PAPR level associated with a probability of 0.1 %.

② Alternate Procedure for PAPR

Use one of the procedures presented in 5.2(ANSI C63.26-2015) to measure the total peak power and record as P_{Pk} .

Use one of the applicable procedures presented 5.2(ANSI C63.26-2015) to measure the total average power and record as P_{Avg} . Determine the P.A.R. from:

$$P.A.R. (dB) = P_{Pk} (dBm) - P_{Avg} (dBm) \quad (P_{Avg} = \text{Average Power} + \text{Duty cycle Factor})$$

Test Settings(Peak Power)

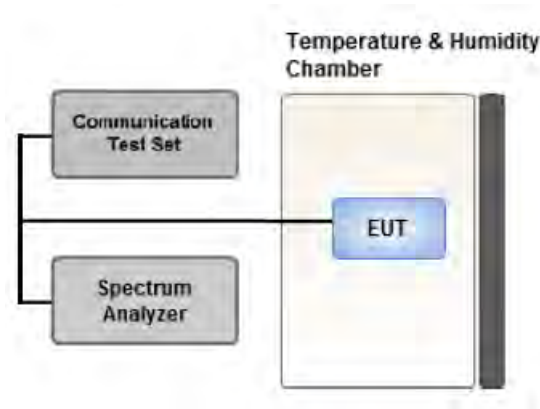
The measurement instrument must have a RBW that is greater than or equal to the OBW of the signal to be measured and a VBW $\geq 3 \times$ RBW.

1. Set the RBW \geq OBW.
2. Set VBW $\geq 3 \times$ RBW.
3. Set span $\geq 2 \times$ OBW.
4. Sweep time $\geq 10 \times$ (number of points in sweep) \times (transmission symbol period).
5. Detector = peak.
6. Trace mode = max hold.
7. Allow trace to fully stabilize.
8. Use the peak marker function to determine the peak amplitude level.

Test Settings(Average Power)

1. Set span to $2 \times$ to $3 \times$ the OBW.
2. Set RBW \geq OBW.
3. Set VBW $\geq 3 \times$ RBW.
4. Set number of measurement points in sweep $\geq 2 \times$ span / RBW.
5. Sweep time:
Set $\geq [10 \times$ (number of points in sweep) \times (transmission period)] for single sweep (automation-compatible) measurement. The transmission period is the (on + off) time.
6. Detector = power averaging (rms).
7. Set sweep trigger to "free run."
8. Trace average at least 100 traces in power averaging (rms) mode if sweep is set to auto-couple. (To accurately determine the average power over the on and off period of the transmitter, it can be necessary to increase the number of traces to be averaged above 100 or, if using a manually configured sweep time, increase the sweep time.)
9. Use the peak marker function to determine the maximum amplitude level.
10. Add $[10 \log (1/\text{duty cycle})]$ to the measured maximum power level to compute the average power during continuous transmission. For example, add $[10 \log (1/0.25)] = 6 \text{ dB}$ if the duty cycle is a constant 25 %.

3.5 OCCUPIED BANDWIDTH.



Test setup

The width of a frequency band such that, below the lower and above the upper frequency limits, the mean powers emitted are each equal to a specified percentage 0.5 % of the total mean power of a given emission.

The EUT makes a call to the communication simulator.

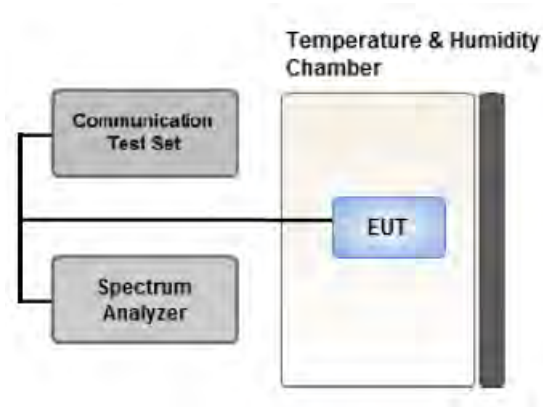
The conducted occupied bandwidth used the power splitter via EUT RF power connector between simulation base station and spectrum analyzer.

The communication simulator station system controlled a EUT to export maximum output power under transmission mode and specific channel frequency. Use OBW measurement function of Spectrum analyzer to measure 99 % occupied bandwidth

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99 % occupied bandwidth and the 26 dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 - 5 % of the expected OBW
3. VBW \geq 3 x RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 - 7 were repeated after changing the RBW such that it would be within 1 - 5 % of the 99 % occupied bandwidth observed in Step 7

3.6 SPURIOUS AND HARMONIC EMISSIONS AT ANTENNA TERMINAL



Test setup

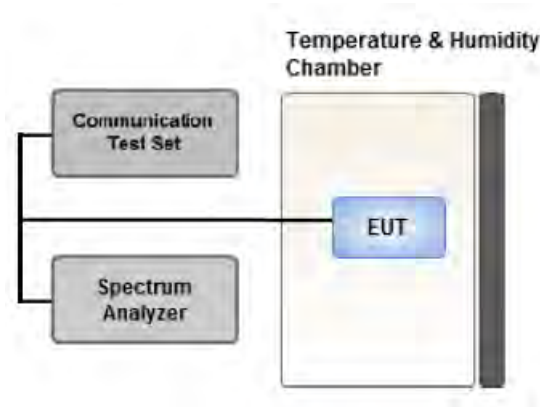
Test Overview

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Settings

1. RBW = 1 MHz
2. VBW \geq 3 MHz
3. Detector = RMS
4. Trace Mode = trace average
5. Sweep time = auto
6. Number of points in sweep \geq 2 x Span / RBW

3.7 BAND EDGE



Test setup

Test Overview

All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Settings

1. Start and stop frequency were set such that the band edge would be placed in the center of the plot
2. Span was set large enough so as to capture all out of band emissions near the band edge
3. RBW > 1 % of the emission bandwidth
4. VBW > 3 x RBW
5. Detector = RMS
6. Number of sweep points $\geq 2 \times \text{Span}/\text{RBW}$
7. Trace mode = trace average
8. Sweep time = auto couple
9. The trace was allowed to stabilize

Test Notes

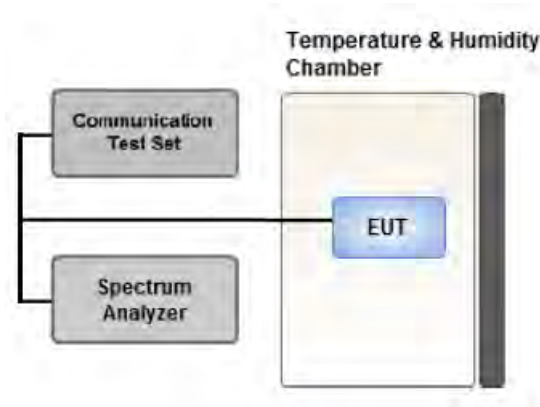
According to FCC 22.917, 24.238, 27.53 specified that power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least $43 + 10 \log(P)$ dB. In the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed.

All measurements were done at 2 channels (low and high operational frequency range.)

The band edge measurement used the power splitter via EUT RF power connector between simulation base station and spectrum analyzer.

Where Margin < 1 dB the emission level is either corrected by $10 \log(1 \text{ MHz} / \text{RB})$ or the emission is integrated over a 1 MHz bandwidth to determine the final result. When using the integration method the integration window is either centered on the emission or, for emissions at the band edge, centered by an offset of 500 kHz from the block edge so that the integration window is the 1 MHz adjacent to the block edge.

3.8 FREQUENCY STABILITY / VARIATION OF AMBIENT TEMPERATURE



Test setup

Test Overview

Frequency stability testing is performed in accordance with the guidelines of ANSI C63.26-2015.

The frequency stability of the transmitter is measured by:

1. Temperature:

The temperature is varied from -30 °C to +50 °C in 10 °C increments using an environmental chamber.

2. Primary Supply Voltage:

- Unless otherwise specified, vary primary supply voltage from 85 % to 115 % of the nominal value for other than hand carried battery equipment.

- For hand carried, battery powered equipment, reduce the primary ac or dc supply voltage to the battery operating end point, which shall be specified by the manufacturer.

Test Settings

1. The carrier frequency of the transmitter is measured at room temperature (20 °C to provide a reference).

2. The equipment is turned on in a “standby” condition for fifteen minutes before applying power to the transmitter.

Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.

3. Frequency measurements are made at 10 °C intervals ranging from -30 °C to +50 °C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

3.9 WORST CASE(RADIATED TEST)

- Waveform : All Waveform of operation were investigated and the worst case configuration results are reported.
(Worst case: DFT-S-OFDM)
- The EUT was tested in three orthogonal planes(X, Y, Z) and in all possible test configurations and positioning.
- The EUT was tested in three modes(Open, Half-open, Closed), the worst case configuration results are reported. (Worst case: Open mode)
- All modes of operation were investigated and the worst case configuration results are reported.
Mode: NSA, SA
Worst case: SA
Mode : Stand alone, Stand alone + External accessories (Earphone, AC adapter, etc)
Worst case : Stand alone
- We were performed the RSE test in condition of co-location.
Mode : Stand alone, Simultaneous transmission scenarios
Worst case : Stand alone
- Radiated Spurious emissions are measured while operating in EN-DC mode with Sub 6 NR carrier as well as an LTE carrier (anchor).
All EN-DC mode of operation (=anchor) were investigated and the test results were measured No Peak Found.
The test results which are attenuated more than 20 dB below the permissible value, so it was not reported.
- All RB sizes, offsets of operation were investigated and the worst case configuration results are reported.
Please refer to the table below.
- In the case of radiated spurious emissions, all bandwidth of operation was investigated and the worst case bandwidth results are reported. (Worst case : 5 MHz)
- SM-F741U & additional models were tested and the worst case results are reported.
(Worst case : SM-F741U)

[Worst case]

Test Description	Modulation	RB size	RB offset	Axis
Effective Radiated Power	PI/2 BPSK, QPSK, 16QAM, 64QAM, 256QAM	See Section 8.1		X
Radiated Spurious and Harmonic Emissions	PI/2 BPSK	See Section 8.1		X

3.10 WORST CASE(CONDUCTED TEST)

- Waveform : All Waveform of operation were investigated and the worst case configuration results are reported.
(Worst case: DFT-S-OFDM)
- Modulation : All Modulation of operation were investigated and the worst case configuration results are reported.
(Worst case: PI/2 BPSK)
- All modes of operation were investigated and the worst case configuration results are reported.
Mode: NSA, SA
Worst case: SA
- All RB sizes, offsets of operation were investigated and the worst case configuration results are reported.
Please refer to the table below.
- SM-F741U & additional models were tested and the worst case results are reported.
(Worst case : SM-F741U)

[Worst case]

Test Description	Modulation	Bandwidth (MHz)	Frequency	RB size	RB offset
Occupied Bandwidth Peak- to- Average Ratio	PI/2 BPSK, QPSK, 16QAM, 64QAM, 256QAM	5, 10, 15	Mid	Full RB	0
Band Edge	PI/2 BPSK	5	Low	1	0
			High	1	24
		10	Low	1	0
			High	1	51
		15	Low	1	0
			High	1	78
5, 10, 15	Low, High	Full RB	0		
	Spurious and Harmonic Emissions at Antenna Terminal	PI/2 BPSK	5, 10, 15	Low, Mid, High	1

4. LIST OF TEST EQUIPMENT

Equipment	Model	Manufacture	Serial No.	Due to Calibration	Calibration Interval
Precision Dipole Antenna	UHAP	Schwarzbeck	01273	03/10/2026	Biennial
Precision Dipole Antenna	UHAP	Schwarzbeck	01274	03/10/2026	Biennial
Horn Antenna(1~18 GHz)	BBHA 9120D	Schwarzbeck	02289	02/14/2026	Biennial
Horn Antenna(1~18 GHz)	BBHA 9120D	Schwarzbeck	9120D-1299	04/27/2025	Biennial
Horn Antenna(15~40 GHz)	BBHA 9170	Schwarzbeck	BBHA9170342	09/29/2024	Biennial
Horn Antenna(15~40 GHz)	BBHA 9170	Schwarzbeck	BBHA9170124	03/28/2025	Biennial
Loop Antenna(9 kHz~30 MHz)	FMZB1513	Rohde & Schwarz	1513-175	01/16/2025	Biennial
Bilog Antenna	VULB9160	Schwarzbeck	3150	03/09/2025	Biennial
Hybrid Antenna	VULB9160	Schwarzbeck	760	02/24/2025	Biennial
RF Switching System	FBSR-06B (1G HPF + LNA)	T&M SYSTEM	F3L1	05/22/2024	Annual
RF Switching System	FBSR-06B (3G HPF + LNA)	T&M SYSTEM	F3L2	05/22/2024	Annual
RF Switching System	FBSR-06B (6G HPF + LNA)	T&M SYSTEM	F3L3	05/22/2024	Annual
RF Switching System	FBSR-06B (LNA)	T&M SYSTEM	F3L4	05/22/2024	Annual
Power Amplifier	CBL18265035	CERNEX	22966	11/17/2024	Annual
Power Amplifier	CBL26405040	CERNEX	25956	02/26/2025	Annual
DC Power Supply	E3632A	Hewlett Packard	MY40004427	08/25/2024	Annual
Power Splitter(DC~26.5 GHz)	11667B	Hewlett Packard	11275	02/29/2025	Annual
Chamber	SU-642	ESPEC	93008124	02/19/2025	Annual
Signal Analyzer(10 Hz~26.5 GHz)	N9020A	Agilent	MY51110063	04/04/2025	Annual
ATTENUATOR(20 dB)	8493C	Hewlett Packard	17280	04/17/2025	Annual
Spectrum Analyzer(10 Hz~40 GHz)	FSV40	REOHDE & SCHWARZ	101436	02/13/2025	Annual
Base Station	8960 (E5515C)	Agilent	MY48360800	08/10/2024	Annual
Wideband Radio Communication Tester	MT8821C	Anritsu Corp.	6262287701	05/22/2024	Annual
Wideband Radio Communication Tester	MT8000A	Anritsu Corp.	6262302511	05/23/2024	Annual
SIGNAL GENERATOR (100 kHz~40 GHz)	SMB100A	REOHDE & SCHWARZ	177633	06/22/2024	Annual
Signal Analyzer(5 Hz~40.0 GHz)	N9030B	KEYSIGHT	MY55480167	05/24/2024	Annual
4-Way Divider	ZC4PD-K1844+	Mini-Circuits	942907	09/19/2024	Annual
FCC LTE Mobile Conducted RF Automation Test Software	-	HCT CO., LTD.,	-	-	-

Note:

1. Equipment listed above that has a calibration due date during the testing period, the testing is completed before equipment expiration date.
2. Especially, all antenna for measurement is calibrated in accordance with the requirements of C63.5 (Version : 2017).

5. MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.4:2014.

All measurement uncertainty values are shown with a coverage factor of $k=2$ to indicate a 95 % level of confidence. The measurement data shown herein meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Parameter	Expanded Uncertainty (\pm dB)
Conducted Disturbance (150 kHz ~ 30 MHz)	1.98 (Confidence level about 95 %, $k=2$)
Radiated Disturbance (9 kHz ~ 30 MHz)	4.36 (Confidence level about 95 %, $k=2$)
Radiated Disturbance (30 MHz ~ 1 GHz)	5.70 (Confidence level about 95 %, $k=2$)
Radiated Disturbance (1 GHz ~ 18 GHz)	5.52 (Confidence level about 95 %, $k=2$)
Radiated Disturbance (18 GHz ~ 40 GHz)	5.66 (Confidence level about 95 %, $k=2$)
Radiated Disturbance (Above 40 GHz)	5.58 (Confidence level about 95 %, $k=2$)

6. SUMMARY OF TEST RESULTS

6.1 Test Condition : Conducted Test

Test Description	FCC Part Section(s)	Test Limit	Test Result
Occupied Bandwidth	§ 2.1049	N/A	PASS
Band Edge / Spurious and Harmonic Emissions at Antenna Terminal.	§ 2.1051, § 27.53(g)	< 43 + 10log10 (P[Watts]) at Band Edge and for all out-of-band emissions	PASS
Conducted Output Power	§ 2.1046	N/A	<u>See Note1</u>
Frequency stability / variation of ambient temperature	§ 2.1055, § 27.54	Emission must remain in band	PASS

Note:

1. See SAR Report
2. Conducted test were tested using 5G Wireless Tester.

6.2 Test Condition : Radiated Test

Test Description	FCC Part Section(s)	Test Limit	Test Result
Effective Radiated Power	§ 27.50(c)(10)	< 3 Watts max. ERP	PASS
Radiated Spurious and Harmonic Emissions	§ 2.1053, § 27.53(g)	< 43 + 10log10 (P[Watts]) for all out-of band emissions	PASS

Note:

1. Radiated tests were tested using 5G Wireless Tester.

7. SAMPLE CALCULATION

7.1 ERP Sample Calculation

Ch./ Freq.		Measured Level (dBm)	Substitute Level (dBm)	Ant. Gain (dBd)	C.L	Pol.	ERP	
channel	Freq.(MHz)						W	dBm
128	824.20	-21.37	38.40	-10.61	0.95	H	0.483	26.84

$$\text{ERP} = \text{Substitute LEVEL(dBm)} + \text{Ant. Gain} - \text{CL(Cable Loss)}$$

- 1) The EUT mounted on a non-conductive turntable is 2.5 meter above test site ground level.
- 2) During the test, the turn table is rotated until the maximum signal is found.
- 3) Record the field strength meter's level.
- 4) Replace the EUT with dipole/Horn antenna that is connected to a calibrated signal generator.
- 5) Increase the signal generator output till the field strength meter's level is equal to the item (3).
- 6) The signal generator output level with Ant. Gain and cable loss are the rating of effective radiated power.

7.2 EIRP Sample Calculation

Ch./ Freq.		Measured Level (dBm)	Substitute Level (dBm)	Ant. Gain (dBi)	C.L	Pol.	EIRP	
channel	Freq.(MHz)						W	dBm
20175	1,732.50	-15.75	18.45	9.90	1.76	H	0.456	26.59

$$\text{EIRP} = \text{Substitute LEVEL(dBm)} + \text{Ant. Gain} - \text{CL(Cable Loss)}$$

- 1) The EUT mounted on a non-conductive turntable is 2.5 meter above test site ground level.
- 2) During the test, the turn table is rotated until the maximum signal is found.
- 3) Record the field strength meter's level.
- 4) Replace the EUT with dipole/Horn antenna that is connected to a calibrated signal generator.
- 5) Increase the signal generator output till the field strength meter's level is equal to the item (3).
- 6) The signal generator output level with Ant. Gain and cable loss are the rating of equivalent isotropic radiated power.

7.3. Emission Designator

GSM Emission Designator

Emission Designator = 249KGXW

GSM BW = 249 kHz

G = Phase Modulation

X = Cases not otherwise covered

W = Combination (Audio/Data)

EDGE Emission Designator

Emission Designator = 249KG7W

GSM BW = 249 kHz

G = Phase Modulation

7 = Quantized/Digital Info

W = Combination (Audio/Data)

WCDMA Emission Designator

Emission Designator = 4M17F9W

WCDMA BW = 4.17 MHz

F = Frequency Modulation

9 = Composite Digital Info

W = Combination (Audio/Data)

QPSK Modulation

Emission Designator = 4M48G7D

LTE BW = 4.48 MHz

G = Phase Modulation

7 = Quantized/Digital Info

D = Data transmission; telemetry; telecommand

QAM Modulation

Emission Designator = 4M48W7D

LTE BW = 4.48 MHz

W = Amplitude/Angle Modulated

7 = Quantized/Digital Info

D = Data transmission; telemetry; telecommand

8. TEST DATA

8.1 EFFECTIVE RADIATED POWER

Freq (MHz)	Mod/ Bandwidth [SCS (kHz)]	Modulation	Measured Level (dBm)	Substitute Level (dBm)	Ant. Gain (dBd)	C.L	Pol	Limit	ERP		RB	
									W	W	dBm	Size
701.5	Sub6 n12/ 5 MHz [15 kHz]	PI/2 BPSK	-28.42	30.53	-9.55	1.28	H	< 3.00	0.093	19.70	1	1
		QPSK	-28.53	30.42	-9.55	1.28	H		0.091	19.59		
		16-QAM	-29.65	29.30	-9.55	1.28	H		0.070	18.47		
		64-QAM	-30.98	27.97	-9.55	1.28	H		0.052	17.14		
		256-QAM	-33.53	25.42	-9.55	1.28	H		0.029	14.59		
707.5		PI/2 BPSK	-28.90	29.94	-9.55	1.28	H		0.082	19.11	1	1
		QPSK	-29.00	29.84	-9.55	1.28	H		0.080	19.01		
		16-QAM	-30.10	28.74	-9.55	1.28	H		0.062	17.91		
		64-QAM	-31.44	27.40	-9.55	1.28	H		0.045	16.57		
		256-QAM	-33.94	24.90	-9.55	1.28	H		0.026	14.07		
713.5	PI/2 BPSK	-29.75	29.38	-9.55	1.28	H	0.072	18.55	1	1		
	QPSK	-29.76	29.37	-9.55	1.28	H	0.071	18.54				
	16-QAM	-30.79	28.34	-9.55	1.28	H	0.056	17.51				
	64-QAM	-32.18	26.95	-9.55	1.28	H	0.041	16.12				
	256-QAM	-34.84	24.29	-9.55	1.28	H	0.022	13.46				

Freq (MHz)	Mod/ Bandwidth [SCS (kHz)]	Modulation	Measured Level (dBm)	Substitute Level (dBm)	Ant. Gain (dBd)	C.L	Pol	Limit	ERP		RB	
									W	W	dBm	Size
704.0		PI/2 BPSK	-28.42	30.49	-9.55	1.28	H	< 3.00	0.092	19.66	1	1
		QPSK	-28.48	30.43	-9.55	1.28	H		0.091	19.60		
		16-QAM	-29.63	29.28	-9.55	1.28	H		0.070	18.45		
		64-QAM	-30.94	27.97	-9.55	1.28	H		0.052	17.14		
		256-QAM	-33.61	25.30	-9.55	1.28	H		0.028	14.47		
707.5	Sub6 n12/ 10 MHz [15 kHz]	PI/2 BPSK	-28.79	30.05	-9.55	1.28	H	< 3.00	0.084	19.22	1	1
		QPSK	-28.82	30.02	-9.55	1.28	H		0.083	19.19		
		16-QAM	-29.95	28.89	-9.55	1.28	H		0.064	18.06		
		64-QAM	-31.06	27.78	-9.55	1.28	H		0.050	16.95		
		256-QAM	-33.88	24.96	-9.55	1.28	H		0.026	14.13		
711.0		PI/2 BPSK	-29.33	29.72	-9.55	1.28	H	< 3.00	0.078	18.89	1	1
		QPSK	-29.41	29.64	-9.55	1.28	H		0.076	18.81		
		16-QAM	-30.56	28.49	-9.55	1.28	H		0.058	17.66		
		64-QAM	-31.86	27.19	-9.55	1.28	H		0.043	16.36		
		256-QAM	-34.62	24.43	-9.55	1.28	H		0.023	13.60		

Freq (MHz)	Mod/ Bandwidth [SCS (kHz)]	Modulation	Measured Level (dBm)	Substitute Level (dBm)	Ant. Gain (dBd)	C.L	Pol	Limit	ERP		RB	
									W	W	dBm	Size
706.5		PI/2 BPSK	-28.45	30.48	-9.55	1.28	H	< 3.00	0.092	19.65	1	1
		QPSK	-28.47	30.46	-9.55	1.28	H		0.092	19.63		
		16-QAM	-29.56	29.37	-9.55	1.28	H		0.071	18.54		
		64-QAM	-30.92	28.01	-9.55	1.28	H		0.052	17.18		
		256-QAM	-33.57	25.36	-9.55	1.28	H		0.028	14.53		
707.5	Sub6 n12/ 15 MHz [15 kHz]	PI/2 BPSK	-28.50	30.34	-9.55	1.28	H	< 3.00	0.089	19.51	1	1
		QPSK	-28.51	30.33	-9.55	1.28	H		0.089	19.50		
		16-QAM	-29.66	29.18	-9.55	1.28	H		0.068	18.35		
		64-QAM	-31.02	27.82	-9.55	1.28	H		0.050	16.99		
		256-QAM	-33.62	25.22	-9.55	1.28	H		0.027	14.39		
708.5		PI/2 BPSK	-28.61	30.26	-9.55	1.28	H	< 3.00	0.088	19.43	1	1
		QPSK	-28.70	30.17	-9.55	1.28	H		0.086	19.34		
		16-QAM	-29.74	29.13	-9.55	1.28	H		0.068	18.30		
		64-QAM	-31.03	27.84	-9.55	1.28	H		0.050	17.01		
		256-QAM	-33.83	25.04	-9.55	1.28	H		0.026	14.21		

8.2 RADIATED SPURIOUS EMISSIONS

▣ NR Band:	<u>N12</u>
▣ Bandwidth:	<u>5 MHz</u>
▣ Modulation:	<u>PI/2 BPSK</u>
▣ Distance:	<u>3 meters</u>
▣ SCS:	<u>15 kHz</u>

Ch	Freq (MHz)	Measured Level (dBm)	Ant. Gain (dBi)	Substitute Level (dBm)	C.L	Pol	Result (dBm)	Limit (dBm)	RB	
									Size	Offset
140300 (701.5)	1 403.00	-58.06	7.40	-63.67	1.80	V	-58.07	-13.00	1	1
	2 104.50	-59.54	9.10	-65.35	2.28	V	-58.53	-13.00		
	2 806.00	-60.84	10.30	-64.79	2.69	V	-57.18	-13.00		
	3 507.50	-60.25	11.20	-63.23	2.95	V	-54.98	-13.00		
	4 209.00	-60.20	11.20	-59.09	3.28	V	-51.17	-13.00		
	4 910.50	-61.14	11.10	-57.37	3.58	V	-49.85	-13.00		
141500 (707.5)	1 415.00	-58.52	7.40	-64.97	1.80	V	-59.37	-13.00	1	1
	2 122.50	-59.55	9.10	-64.75	2.28	V	-57.93	-13.00		
	2 830.00	-59.14	10.30	-63.57	2.69	V	-55.96	-13.00		
	3 537.50	-60.31	11.30	-62.58	3.00	V	-54.28	-13.00		
	4 245.00	-61.39	11.20	-60.94	3.31	V	-53.05	-13.00		
	4 952.50	-60.96	10.90	-56.50	3.58	V	-49.18	-13.00		
142700 (713.5)	1 427.00	-58.70	7.40	-65.50	1.81	V	-59.91	-13.00	1	1
	2 140.50	-57.04	9.10	-61.81	2.30	V	-55.01	-13.00		
	2 854.00	-58.99	10.30	-62.80	2.71	V	-55.21	-13.00		
	3 567.50	-60.48	11.40	-62.80	3.00	V	-54.40	-13.00		
	4 281.00	-61.15	11.20	-59.54	3.33	V	-51.67	-13.00		
	4 994.50	-61.31	10.80	-56.42	3.64	V	-49.26	-13.00		

8.3 PEAK-TO-AVERAGE RATIO

Band	Band Width	Frequency (MHz)	Modulation	Resource Block Size	Resource Block Offset	Data (dB)
Sub6 n12	5 MHz	707.5	BPSK	25	0	4.00
			QPSK			5.18
			16-QAM			6.04
			64-QAM			6.10
			256-QAM			6.01
	10 MHz		BPSK	50		4.01
			QPSK			5.11
			16-QAM			5.95
			64-QAM			6.25
			256-QAM			6.20
	15 MHz		BPSK	75		4.39
			QPSK			5.23
			16-QAM			5.95
			64-QAM			6.25
			256-QAM			6.50

Note:

1. Plots of the EUT's Peak- to- Average Ratio are shown Page 51 ~ 65.

8.4 OCCUPIED BANDWIDTH

Band	Band Width	Frequency (MHz)	Modulation	Resource Block Size	Resource Block Offset	Data (MHz)
Sub6 n12	5 MHz	707.5	BPSK	25	0	4.5992
			QPSK			4.5592
			16-QAM			4.5774
			64-QAM			4.5858
			256-QAM			4.5839
	10 MHz		BPSK	50		8.9573
			QPSK			8.9391
			16-QAM			8.9492
			64-QAM			8.9672
			256-QAM			8.9425
	15 MHz		BPSK	75		13.387
			QPSK			13.415
			16-QAM			13.350
			64-QAM			13.460
			256-QAM			13.441

Note:

1. Plots of the EUT's Occupied Bandwidth are shown Page 36 ~ 50.

8.5 CONDUCTED SPURIOUS EMISSIONS

Band	Band Width (MHz)	Frequency (MHz)	Frequency of Maximum Harmonic (GHz)	Factor (dB)	Measurement Maximum Data (dBm)	Result (dBm)	Limit (dBm)
Sub6 n12	5	701.5	9.4207	31.315	-70.871	-39.556	-13.00
		707.5	8.2697	31.315	-69.676	-38.361	
		713.5	9.1845	31.315	-70.758	-39.443	
	10	704.0	8.2727	31.315	-70.528	-39.213	
		707.5	5.7358	31.315	-70.903	-39.588	
		711.0	8.2677	31.315	-70.049	-38.734	
	15	706.5	6.0170	31.315	-71.172	-39.857	
		707.5	4.9248	30.700	-70.355	-39.655	
		708.5	4.0394	30.700	-69.906	-39.206	

Note:

1. Plots of the EUT's Conducted Spurious Emissions are shown Page 87 ~ 95.
2. Result (dBm) = Measurement Maximum Data (dBm) + Factor (dB)
3. Factor(dB) = Cable Loss + Attenuator + Splitter

Frequency Range (GHz)	Factor [dB]
0.03 - 1	27.994
1 - 5	30.700
5 - 10	31.315
10 - 15	31.840
15 - 20	32.213
Above 20	32.855

8.6 BAND EDGE

- Plots of the EUT's Band Edge are shown Page 66 ~ 86.

8.7 FREQUENCY STABILITY / VARIATION OF AMBIENT TEMPERATURE

- ▣ BandWidth: 5 MHz
- ▣ Voltage(100 %): 3.880 VDC
- ▣ Batt. Endpoint: 3.300 VDC
- ▣ Deviation Limit: Emission must remain in band

Test. Frequency (MHz)	Voltage (%)	Temp. (°C)	Frequency (Hz)	Frequency Error (Hz)	Deviation (%)	ppm
707.5	100 %	+20(Ref)	707 500 002	0.0	0.000 000	0.000
	100 %	-30	707 500 010	7.5	0.000 001	0.011
	100 %	-20	707 500 006	4.1	0.000 001	0.006
	100 %	-10	707 500 005	3.4	0.000 000	0.005
	100 %	0	707 500 005	3.2	0.000 000	0.005
	100 %	+10	707 500 005	3.1	0.000 000	0.004
	100 %	+30	707 500 007	5.4	0.000 001	0.008
	100 %	+40	707 500 005	2.9	0.000 000	0.004
	100 %	+50	707 500 005	2.7	0.000 000	0.004
	Batt. Endpoint	+20	707 500 006	4.3	0.000 001	0.006

- ▣ BandWidth: 10 MHz
- ▣ Voltage(100 %): 3.880 VDC
- ▣ Batt. Endpoint: 3.300 VDC
- ▣ Deviation Limit: Emission must remain in band

Test. Frequency (MHz)	Voltage (%)	Temp. (°C)	Frequency (Hz)	Frequency Error (Hz)	Deviation (%)	ppm
707.5	100 %	+20(Ref)	707 500 014	0.0	0.000 000	0.000
	100 %	-30	707 500 013	-1.4	0.000 000	-0.002
	100 %	-20	707 500 022	7.9	0.000 001	0.011
	100 %	-10	707 500 017	3.3	0.000 000	0.005
	100 %	0	707 500 018	3.9	0.000 001	0.006
	100 %	+10	707 500 018	3.7	0.000 001	0.005
	100 %	+30	707 500 019	4.5	0.000 001	0.006
	100 %	+40	707 500 019	5.1	0.000 001	0.007
	100 %	+50	707 500 018	4.4	0.000 001	0.006
	Batt. Endpoint	+20	707 500 018	3.7	0.000 001	0.005

- ▣ BandWidth: 15 MHz
- ▣ Voltage(100 %): 3.880 VDC
- ▣ Batt. Endpoint: 3.300 VDC
- ▣ Deviation Limit: Emission must remain in band

Test. Frequency (MHz)	Voltage (%)	Temp. (°C)	Frequency (Hz)	Frequency Error (Hz)	Deviation (%)	ppm
707.5	100 %	+20(Ref)	707 500 009	0.0	0.000 000	0.000
	100 %	-30	707 500 019	9.5	0.000 001	0.013
	100 %	-20	707 500 014	4.7	0.000 001	0.007
	100 %	-10	707 500 013	4.3	0.000 001	0.006
	100 %	0	707 500 014	4.5	0.000 001	0.006
	100 %	+10	707 500 014	5.2	0.000 001	0.007
	100 %	+30	707 500 012	2.9	0.000 000	0.004
	100 %	+40	707 500 013	3.9	0.000 001	0.006
	100 %	+50	707 500 014	4.7	0.000 001	0.007
	Batt. Endpoint	+20	707 500 012	3.3	0.000 000	0.005

9. TEST PLOTS

Sub6 n12. Occupied Bandwidth Plot (5M BW Ch.141500 BPSK_RB25_0)



Sub6 n12. Occupied Bandwidth Plot (5M BW Ch.141500 QPSK_RB25_0)



Sub6 n12. Occupied Bandwidth Plot (5M BW Ch.141500 16QAM_RB25_0)



Sub6 n12. Occupied Bandwidth Plot (5M BW Ch.141500 64QAM_RB25_0)



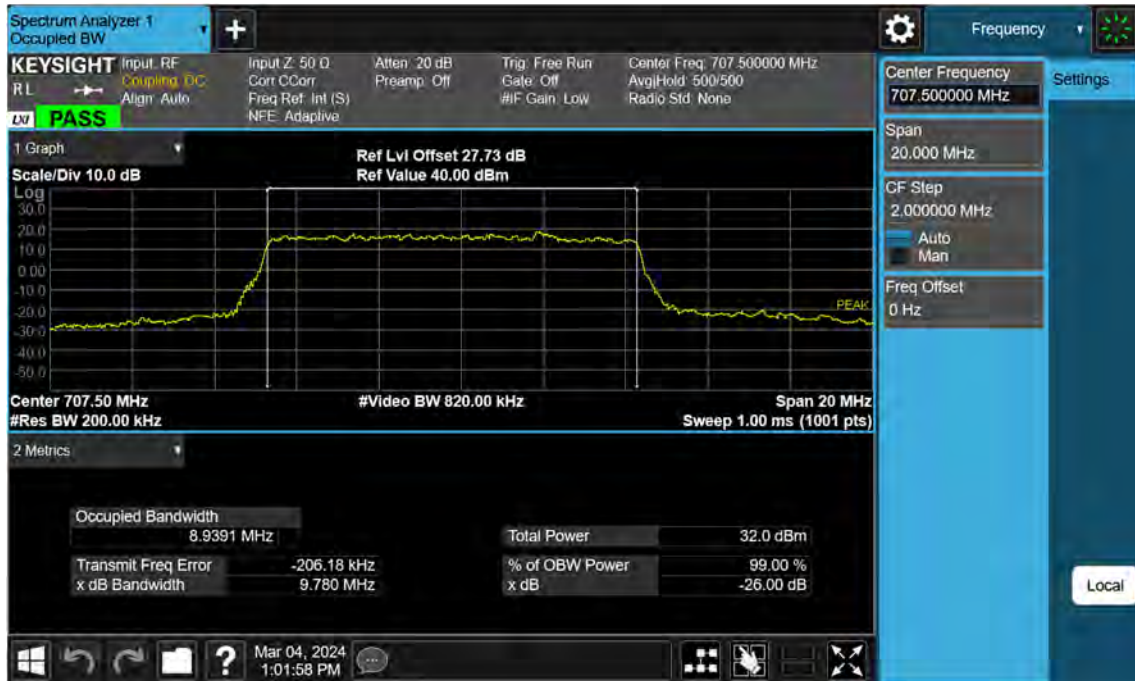
Sub6 n12. Occupied Bandwidth Plot (5M BW Ch.141500 256QAM_RB25_0)



Sub6 n12. Occupied Bandwidth Plot (10M BW Ch.141500 BPSK_RB50_0)



Sub6 n12. Occupied Bandwidth Plot (10M BW Ch.141500 QPSK_RB50_0)



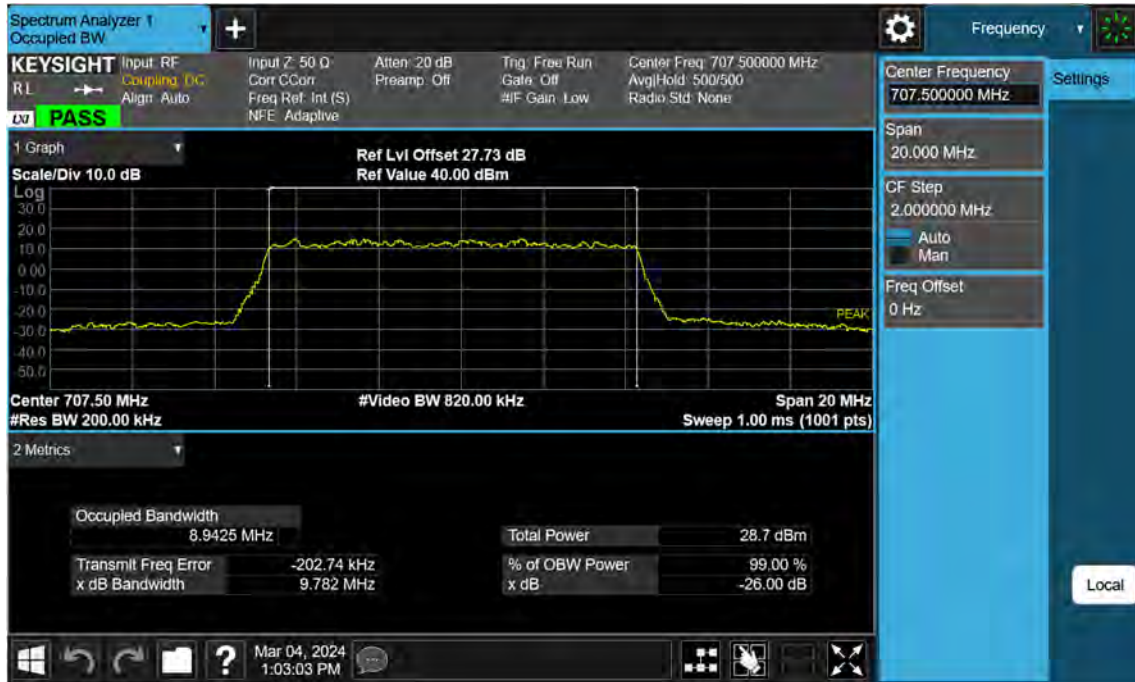
Sub6 n12. Occupied Bandwidth Plot (10M BW Ch.141500 16QAM_RB50_0)



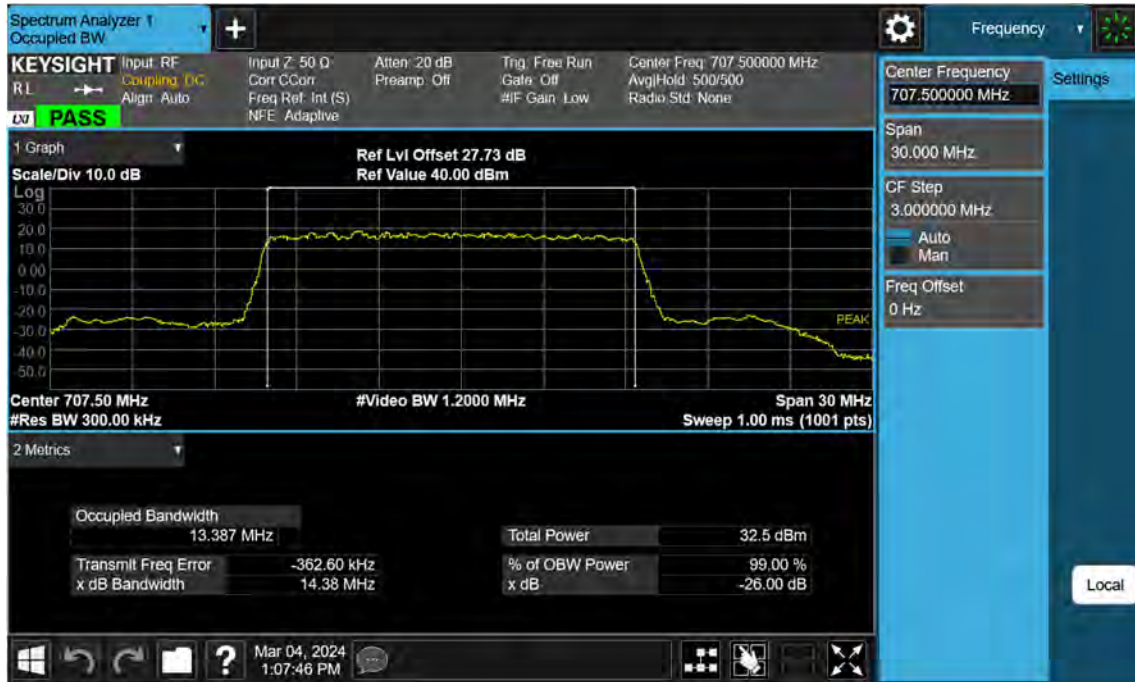
Sub6 n12. Occupied Bandwidth Plot (10M BW Ch.141500 64QAM_RB50_0)



Sub6 n12. Occupied Bandwidth Plot (10M BW Ch.141500 256QAM_RB50_0)



Sub6 n12. Occupied Bandwidth Plot (15M BW Ch.141500 BPSK_RB75_0)



Sub6 n12. Occupied Bandwidth Plot (15M BW Ch.141500 QPSK_RB75_0)



Sub6 n12. Occupied Bandwidth Plot (15M BW Ch.141500 16QAM_RB75_0)



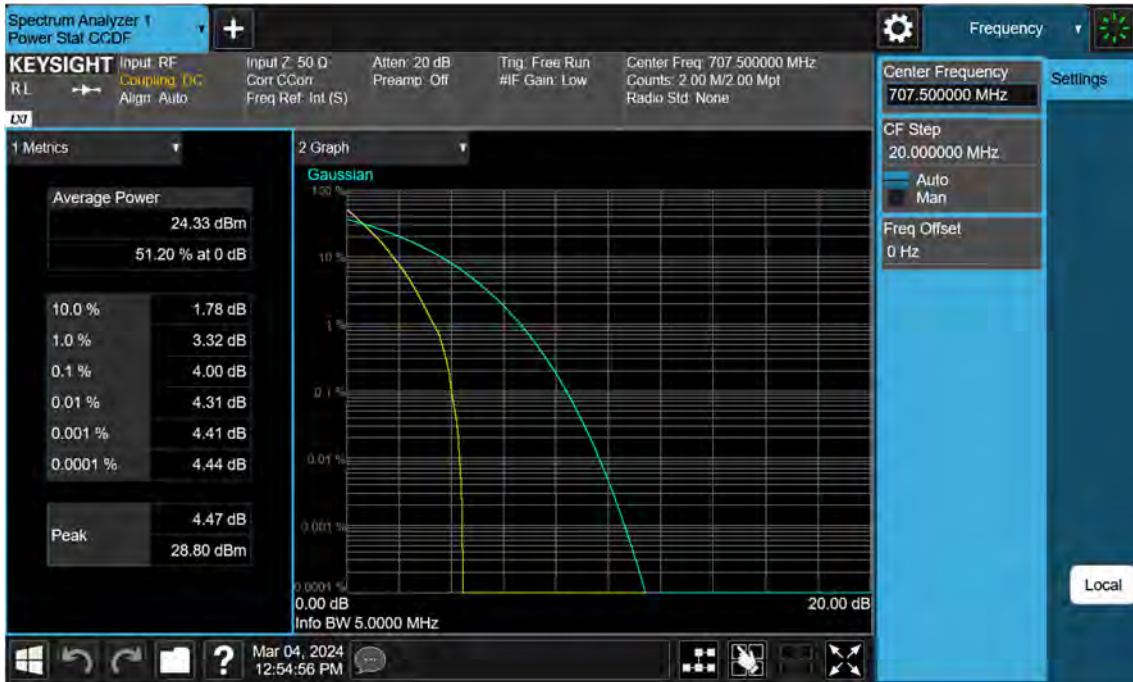
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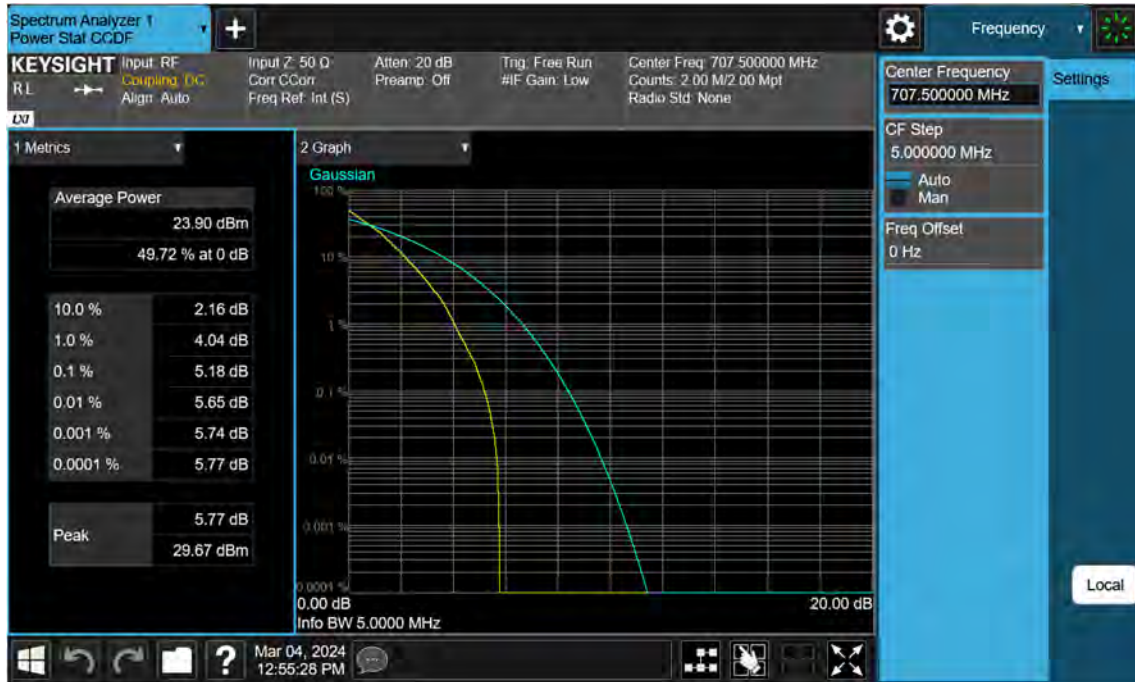
Sub6 n12. Occupied Bandwidth Plot (15M BW Ch.141500 256QAM_RB75_0)



Sub6 n12. PAR Plot (5M BW Ch.141500 BPSK_RB25_0)



Sub6 n12. PAR Plot (5M BW Ch.141500 QPSK_RB25_0)



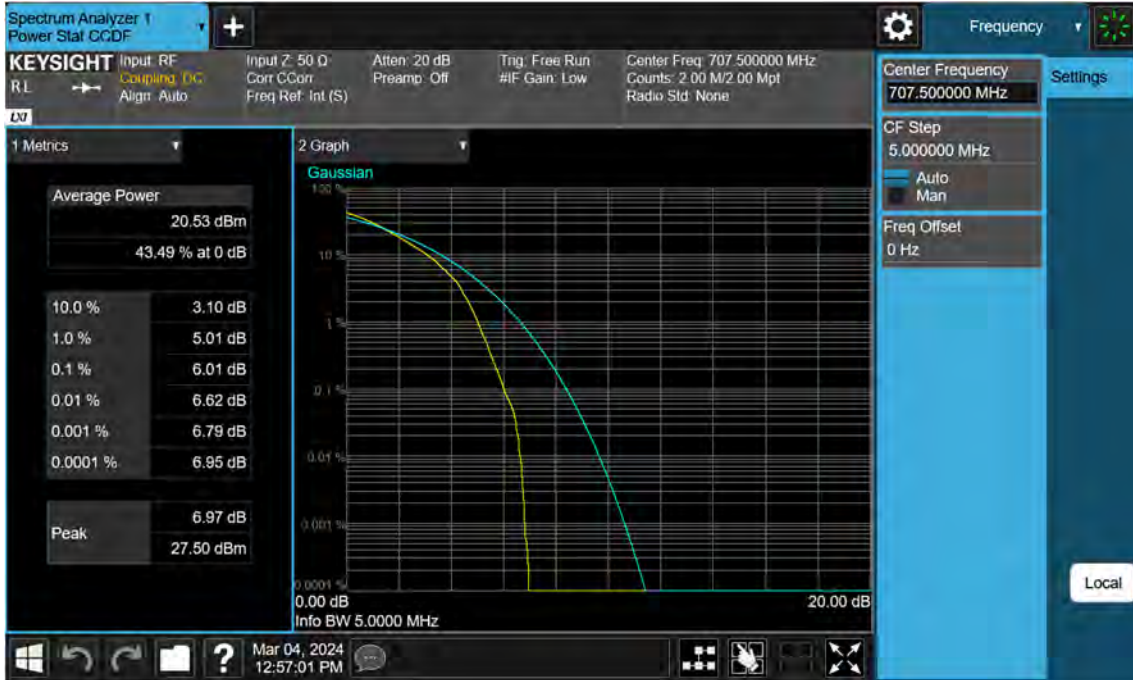
Sub6 n12. PAR Plot (5M BW Ch.141500 16QAM_RB25_0)



Sub6 n12. PAR Plot (5M BW Ch.141500 64QAM_RB25_0)



Sub6 n12. PAR Plot (5M BW Ch.141500 256QAM_RB25_0)



Sub6 n12. PAR Plot (10M BW Ch.141500 BPSK_RB50_0)



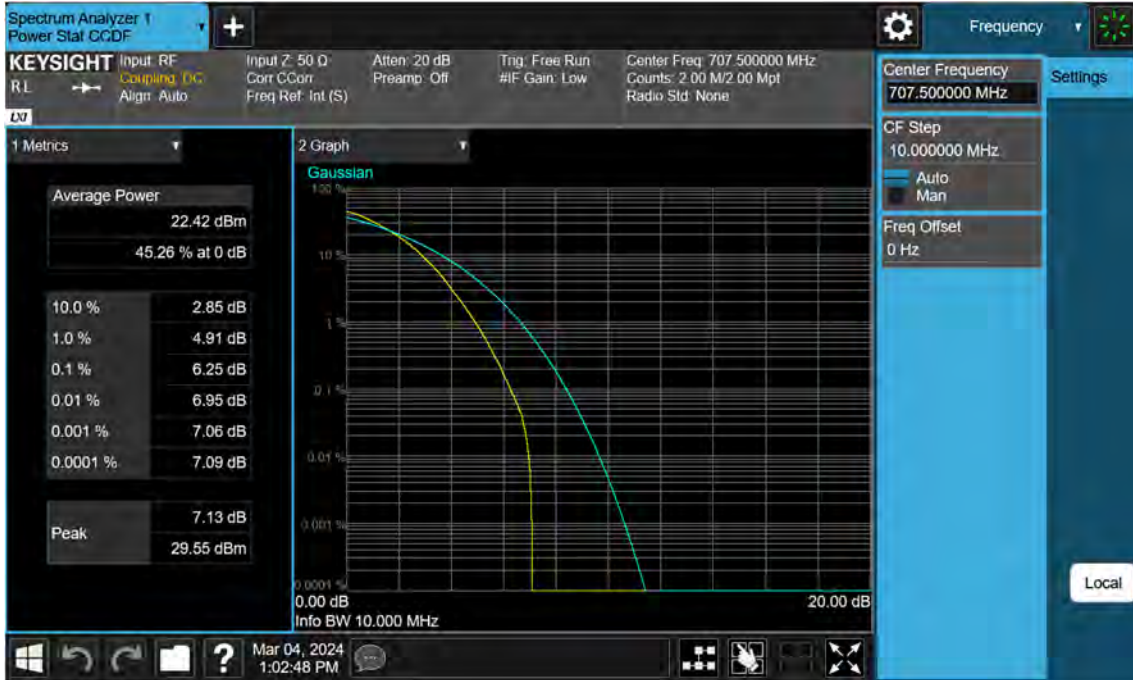
Sub6 n12. PAR Plot (10M BW Ch.141500 QPSK_RB50_0)



Sub6 n12. PAR Plot (10M BW Ch.141500 16QAM_RB50_0)



Sub6 n12. PAR Plot (10M BW Ch.141500 64QAM_RB50_0)



Sub6 n12. PAR Plot (10M BW Ch.141500 256QAM_RB50_0)



Sub6 n12. PAR Plot (15M BW Ch.141500 BPSK_RB75_0)



Sub6 n12. PAR Plot (15M BW Ch.141500 QPSK_RB75_0)



Sub6 n12. PAR Plot (15M BW Ch.141500 16QAM_RB75_0)



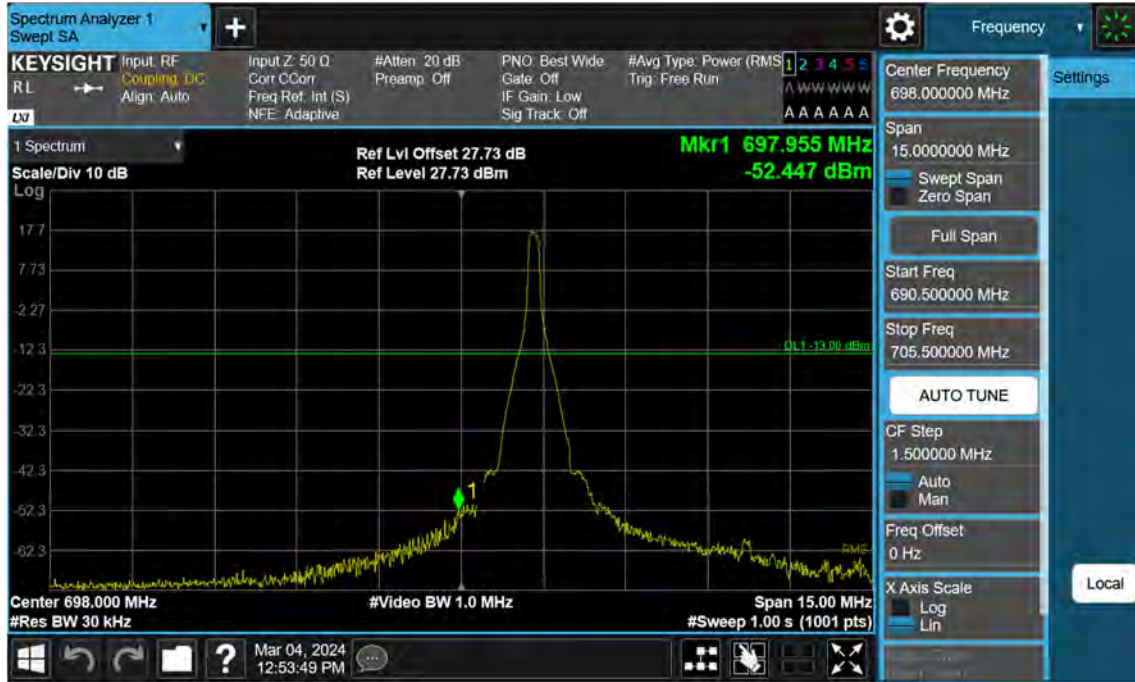
Sub6 n12. PAR Plot (15M BW Ch.141500 64QAM_RB75_0)



Sub6 n12. PAR Plot (15M BW Ch.141500 256QAM_RB75_0)



Sub6 n12. Lower Band Edge Plot (5M BW Ch.140300 BPSK_RB1_Offset 0)



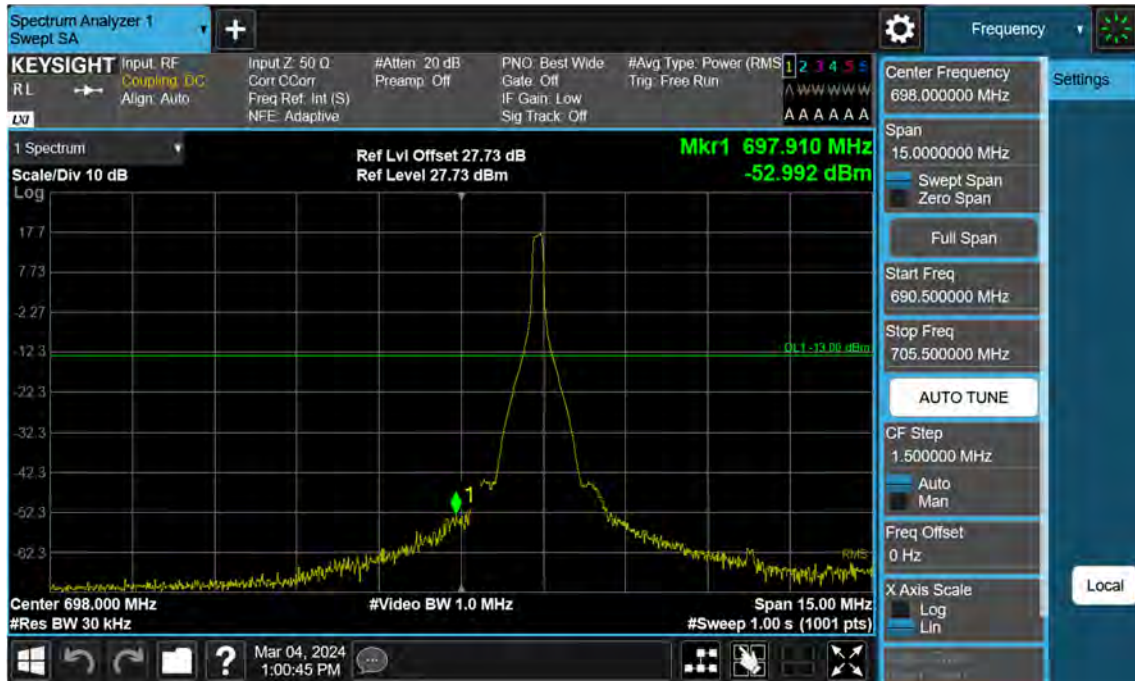
Sub6 n12. Lower Band Edge Plot (5M BW Ch.140300 BPSK_RB25_Offset 0)



Sub6 n12. Lower Extended Band Edge Plot (5M BW Ch.140300 BPSK_RB25_0)



Sub6 n12. Lower Band Edge Plot (10M BW Ch.140800 BPSK_RB1_Offset 0)



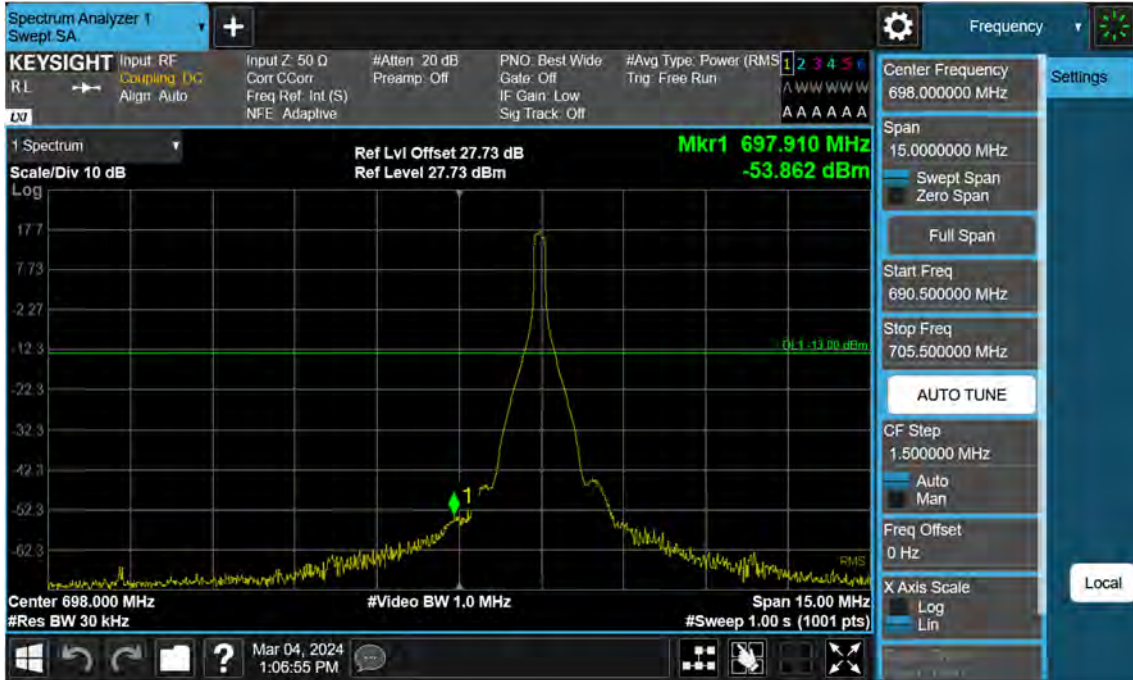
Sub6 n12. Lower Band Edge Plot (10M BW Ch.140800 BPSK_RB50_Offset 0)



Sub6 n12. Lower Extended Band Edge Plot (10M BW Ch.140800 BPSK_RB50_0)



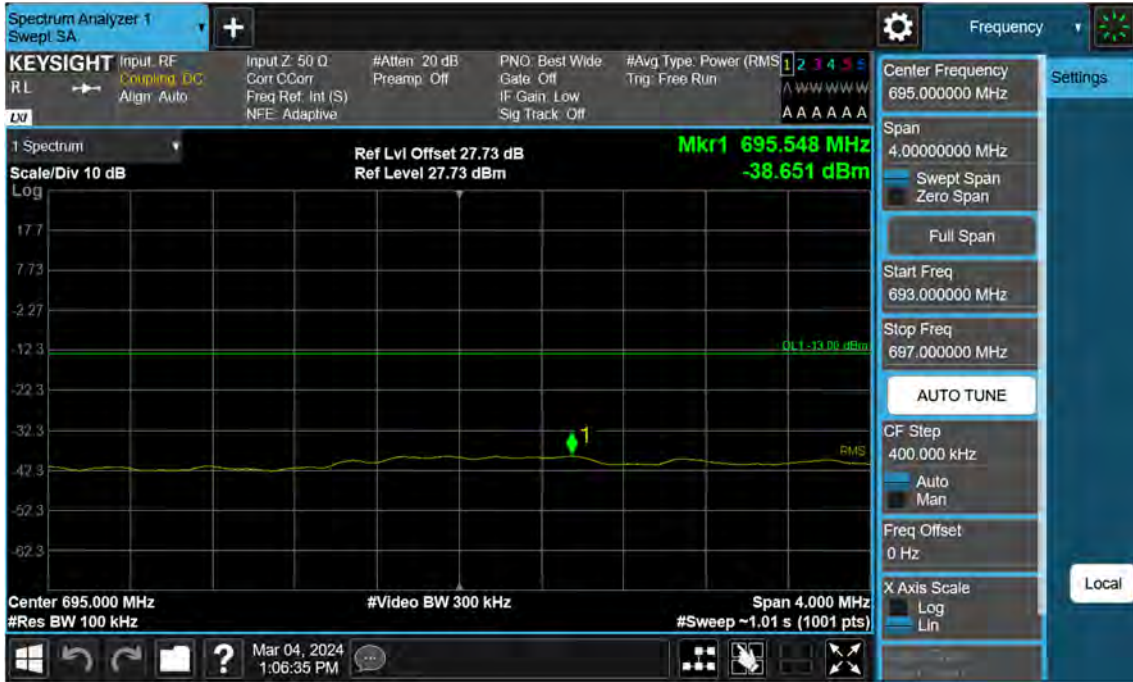
Sub6 n12. Lower Band Edge Plot (15M BW Ch.141300 BPSK_RB1_Offset 0)



Sub6 n12. Lower Band Edge Plot (15M BW Ch.141300 BPSK_RB75_Offset 0)



Sub6 n12. Lower Extended Band Edge Plot (15M BW Ch.141300 BPSK_RB75_0)



Sub6 n12. Upper Band Edge Plot (5M BW Ch.142700 BPSK_RB1_Offset 24)_1



Sub6 n12. Upper Band Edge Plot (5M BW Ch.142700 BPSK_RB1_Offset 24)_2



Sub6 n12. Upper Band Edge Plot (5M BW Ch.142700 BPSK_RB25_Offset 0)



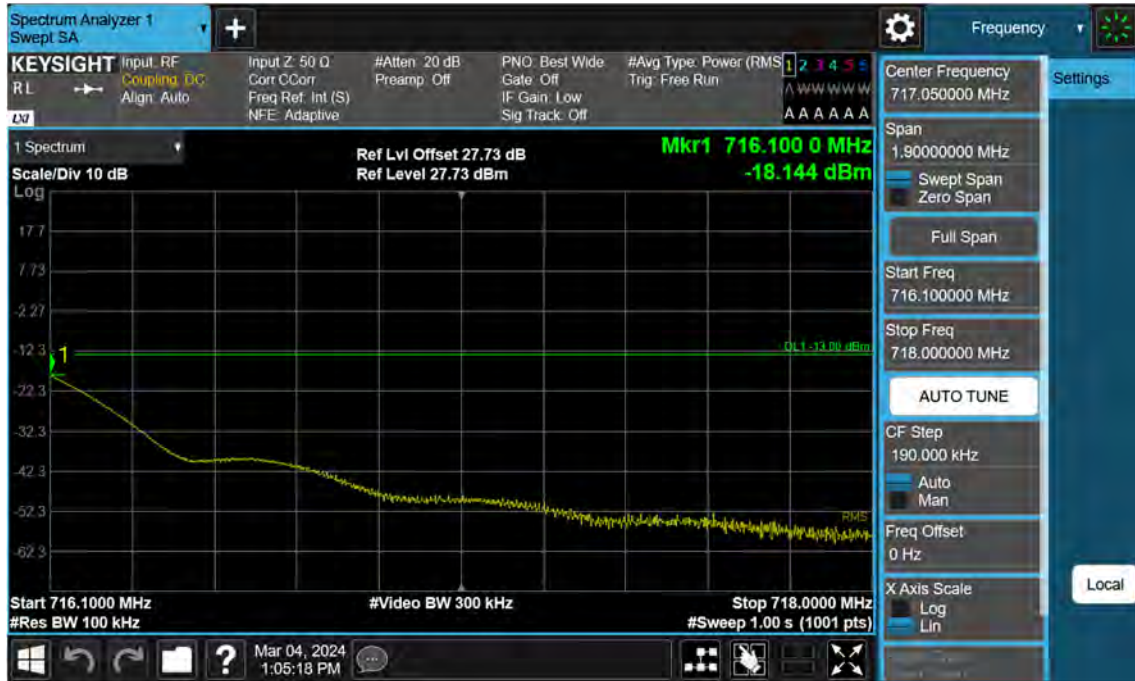
Sub6 n12. Upper Extended Band Edge Plot (5M BW Ch.142700 BPSK_RB25_0)



Sub6 n12. Upper Band Edge Plot (10M BW Ch.142200 BPSK_RB1_Offset 51)_1



Sub6 n12. Upper Band Edge Plot (10M BW Ch.142200 BPSK_RB1_Offset 51)_2



Sub6 n12. Upper Band Edge Plot (10M BW Ch.142200 BPSK_RB50_Offset 0)



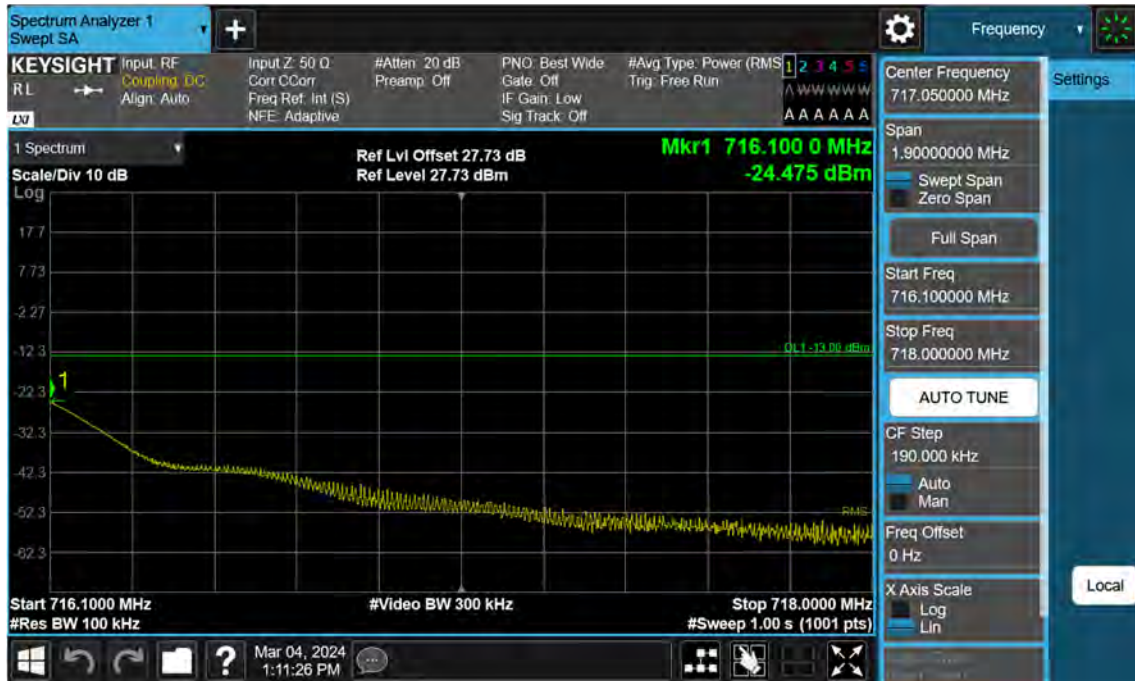
Sub6 n12. Upper Extended Band Edge Plot (10M BW Ch.142200 BPSK_RB50_0)



Sub6 n12. Upper Band Edge Plot (15M BW Ch.141700 BPSK_RB1_Offset 78)_1



Sub6 n12. Upper Band Edge Plot (15M BW Ch.141700 BPSK_RB1_Offset 78)_2



Sub6 n12. Upper Band Edge Plot (15M BW Ch.141700 BPSK_RB75_Offset 0)



Sub6 n12. Upper Extended Band Edge Plot (15M BW Ch.141700 BPSK_RB75_0)



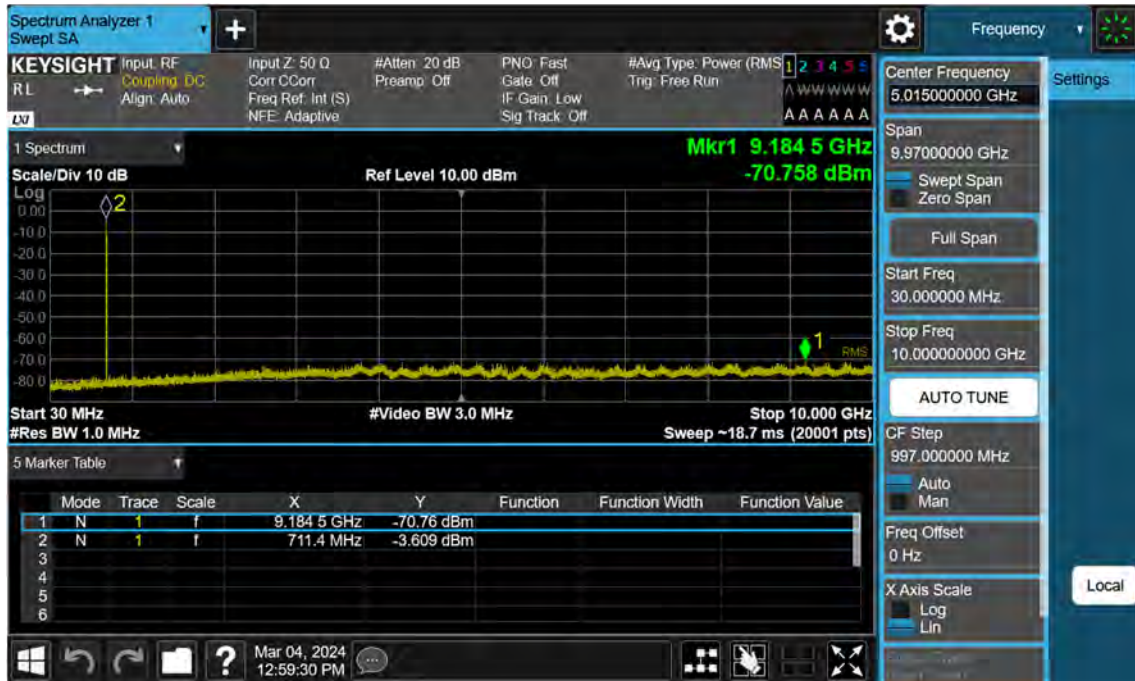
Sub6 n12. Conducted Spurious Plot_ (140300ch_5MHz_BPSK_RB 1_1)



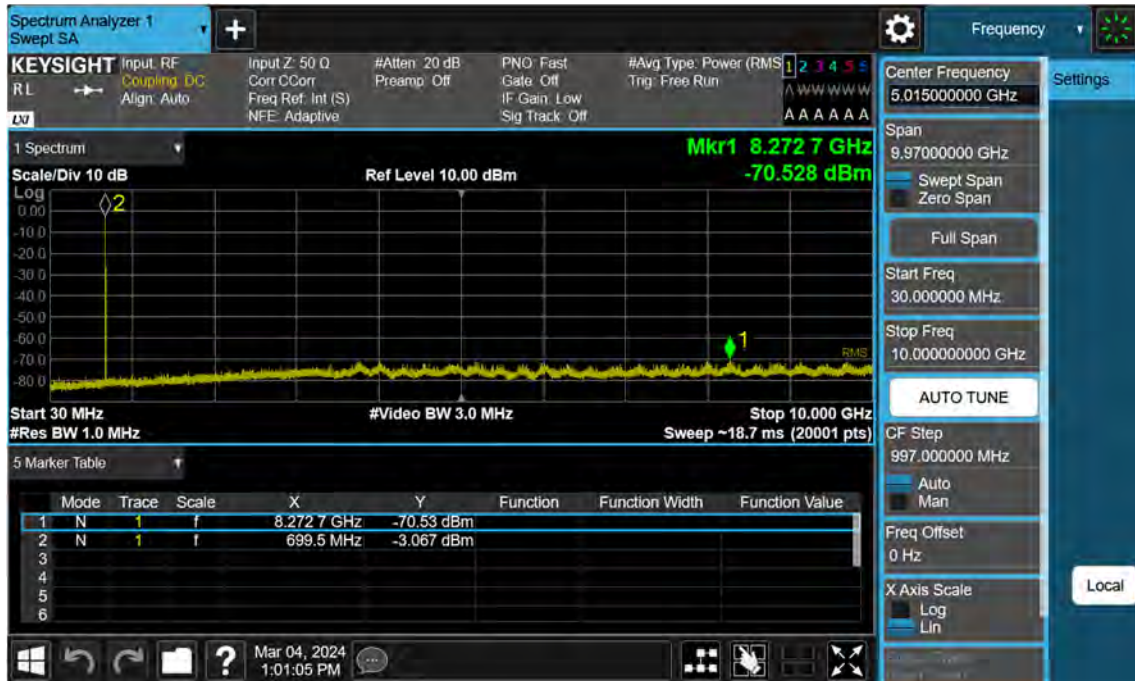
Sub6 n12. Conducted Spurious Plot _ (141500ch_5MHz_BPSK_RB 1_1)



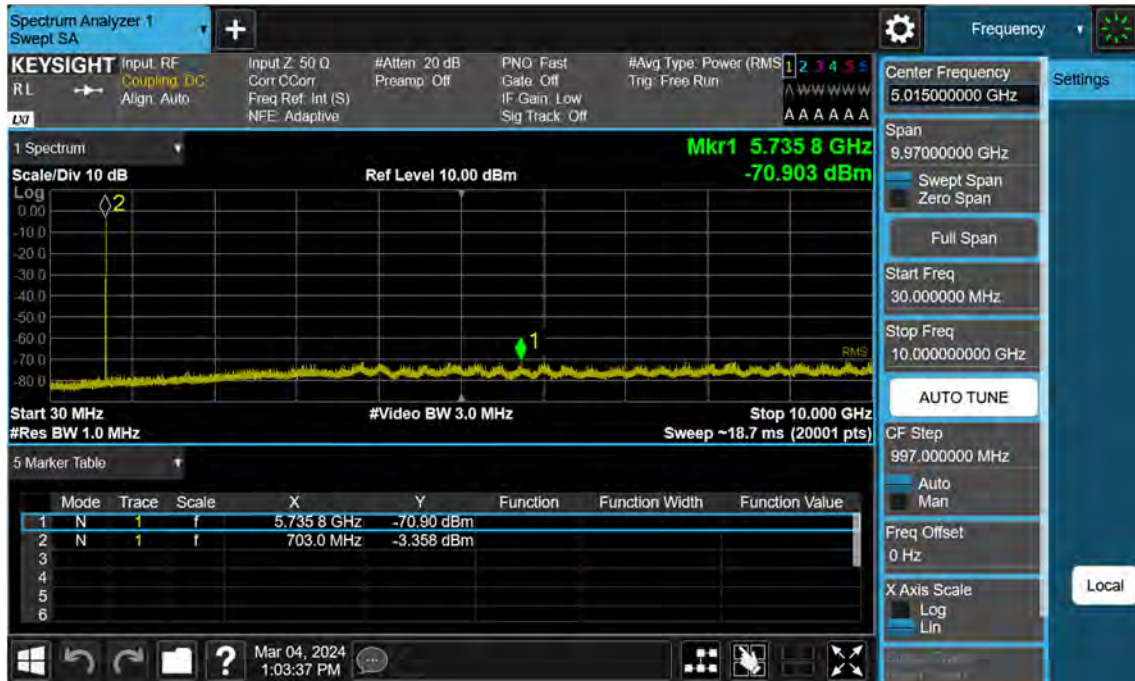
Sub6 n12. Conducted Spurious Plot_ (142700ch_5MHz_BPSK_RB 1_1)



Sub6 n12. Conducted Spurious Plot_ (140800ch_10MHz_BPSK_RB 1_1)



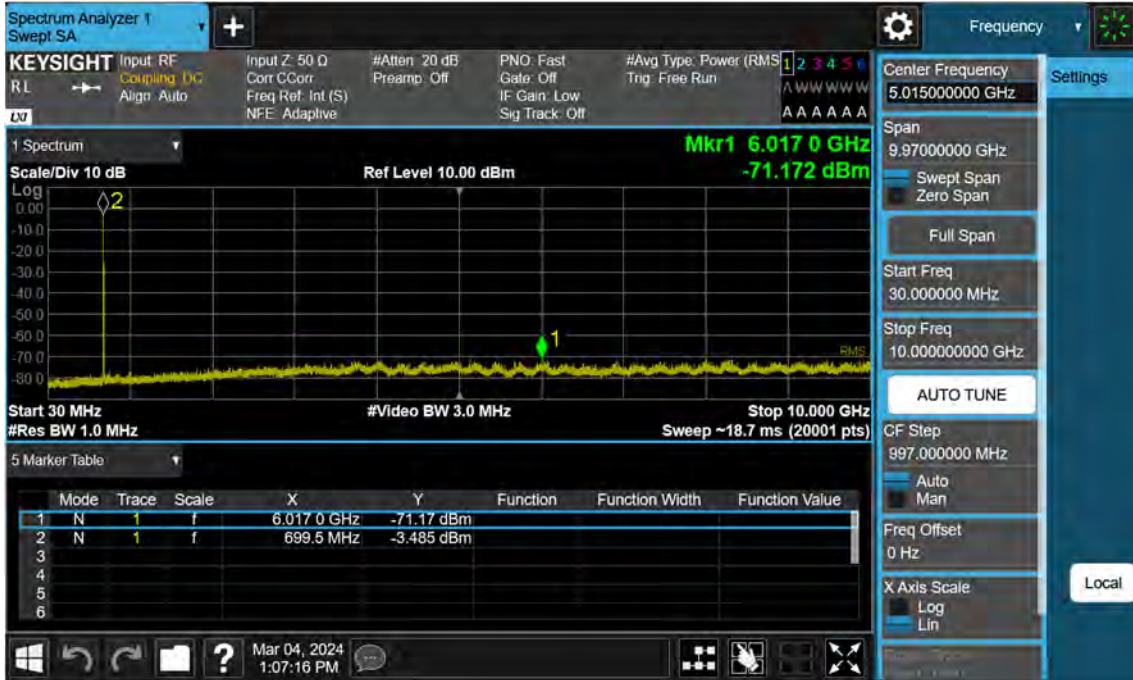
Sub6 n12. Conducted Spurious Plot _ (141500ch_10MHz_BPSK_RB 1_1)



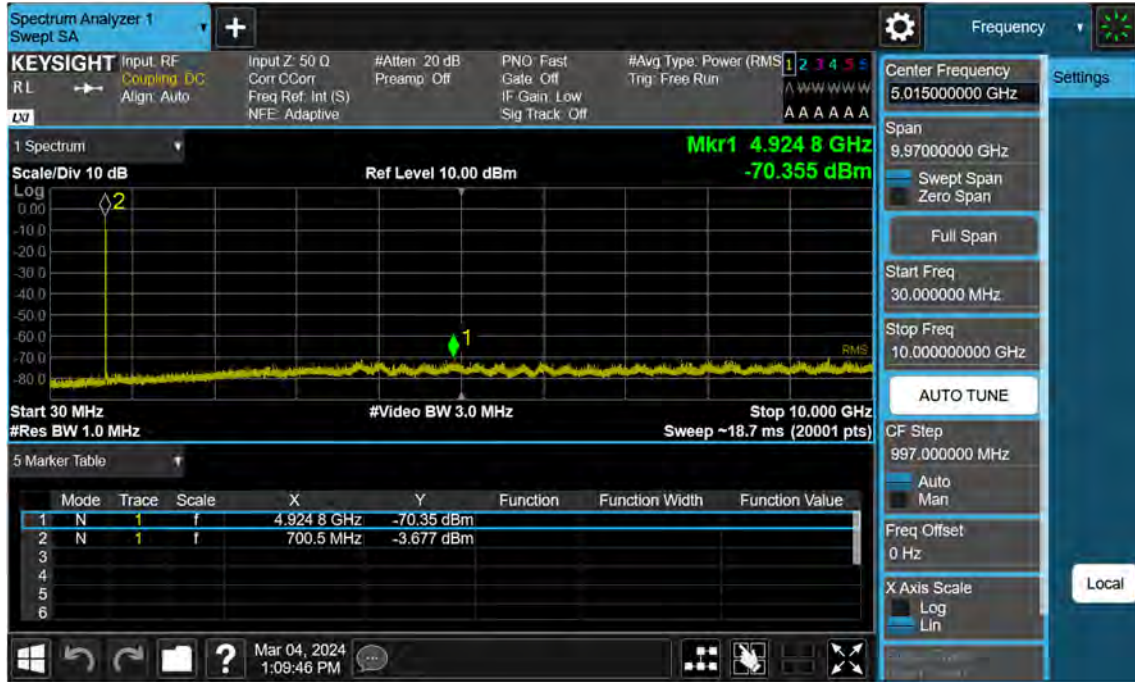
Sub6 n12. Conducted Spurious Plot _ (142200ch_10MHz_BPSK_RB 1_1)



Sub6 n12. Conducted Spurious Plot _ (141300ch_15MHz_BPSK_RB 1_1)



Sub6 n12. Conducted Spurious Plot _ (141500ch_15MHz_BPSK_RB 1_1)



Sub6 n12. Conducted Spurious Plot _ (141700ch_15MHz_BPSK_RB 1_1)



10. ANNEX A_ TEST SETUP PHOTO

Please refer to test setup photo file no. as follows;

No.	Description
1	HCT-RF-2404-FC026-P